### 74ACT11112 DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOP WITH CLEAR AND PRESET

SCAS064A - D3339, JUNE 1989 - REVISED APRIL 1993

- Inputs Are TTL-Voltage Compatible
- Fully Buffered to Offer Maximum Isolation From External Disturbance
- Flow-Through Architecture Optimizes
  PCB Layout
- Center-Pin V<sub>CC</sub> and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

#### **DORNPACKAGE** (TOP VIEW) 1PRE 16**|**1 1J 15 1K 1Q [ 1Q [ 14 1 1CLK 3 GND [ 13 1 1 CLR 12 V<sub>CC</sub> 2<u>Q</u> [ 5 2Q 6 11 2CLR 2PRE 7 10 2CLK 9**∏** 2K 8 2J [

#### description

This device contains two independent J-K negative-edge-triggered flip-flops. A low level at the  $\overline{PRE}$  or  $\overline{CLR}$  input sets or resets the outputs regardless of the levels of the other inputs. When  $\overline{PRE}$  and  $\overline{CLR}$  are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the fall time of the clock pulse. Following the hold-time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by tying J and K high.

The 74ACT11112 is characterized for operation from – 40°C to 85°C.

#### **FUNCTION TABLE**

	INPUTS				OUTI	PUTS
PRE	CLR	CLK	J	K	Q	Q
L	Н	Х	Χ	Х	Н	L
Н	L	X	Χ	X	L	Н
L	L	X	Χ	Χ	Н <sup>†</sup>	Н <sup>†</sup>
Н	Н	$\downarrow$	L	L	Q <sub>0</sub>	$\overline{Q}_0$
Н	Н	$\downarrow$	Н	L	Н	L
Н	Н	$\downarrow$	L	Н	L	Н
Н	Н	$\downarrow$	Н	Н	TOGGLE	
Н	Н	Н	Х	Х	Q <sub>0</sub>	$\overline{Q}_0$

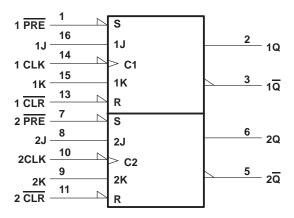
<sup>†</sup> This configuration is nonstable; that is, it will not persist when either PRE or CLR returns to the inactive (high) level.

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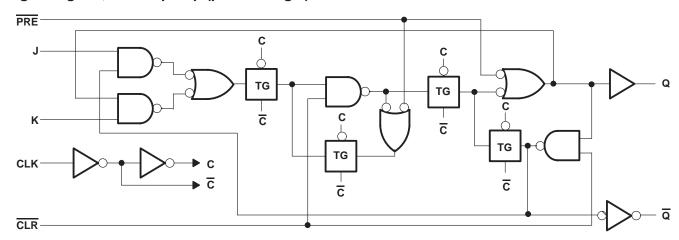
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#### logic symbol<sup>†</sup>



<sup>&</sup>lt;sup>†</sup> This symbol is in accordnace with ANSI/IEEE Std 91-1984 and IEC Publication 617-42.

### logic diagram, each flip-flop (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, VO (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V <sub>CC</sub> or GND	±100 mA
Storage temperature range	– 65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



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## recommended operating conditions

		MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	V
VIH	High-level input voltage	2		V
V <sub>IL</sub>	Low-level input voltage		0.8	V
VI	Input voltage	0	VCC	V
VO	Output voltage	0	VCC	V
IOH	High-level output current		-24	mA
loL	Low-level output current		24	mA
Δt/Δν	Input transition rise or fall rate	0	10	ns/V
TA	Operating free-air temperature	- 40	85	°C

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Voc	T <sub>A</sub> = 25°C			MIN	MAV	UNIT
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	IVIIIV	0.1 0.1 0.44 0.44 1.65 ±1 40	UNIT
	ΙΟΗ = – 50 μΑ	4.5 V	4.4			4.4		
	10Η = - 30 μΑ	5.5 V	5.4			5.4		
Voн	Jour - 24 m/s	4.5 V	3.94			3.8		V
	IOH = - 24 mA	5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	Jan = 50 uA	4.5 V			0.1		0.1	
	I <sub>OL</sub> = 50 μA	5.5 V			0.1		0.1	
VOL	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.1 0.44 0.44 1.65 ±1	V
	10L = 24 IIIA	5.5 V			0.36		0.44	
	I <sub>OL</sub> = 75 mA <sup>†</sup>	5.5 V					1.65	
IĮ	$V_I = V_{CC}$ or GND	5.5 V			± 0.1		±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40	μΑ
Δl <sub>CC</sub> ‡	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			0.9		1	mA
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		3.5				pF

Those more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			T <sub>A</sub> = 2	25°C	MIN	MAX	UNIT
			MIN	MAX	IVIIN IN	IVIAA	UNIT
fclock	Clock frequency			125		125	MHz
	Pulse duration	PRE or CLR low	4		4		20
t <sub>W</sub>	ruise duration	CLK high or low	4		4		ns
	Catua tima hafara CLK	Data high or low	3.5		4.5		
t <sub>su</sub>	Setup time before CLK↓	PRE or CLR inactive	2		2		ns
t <sub>h</sub>	Hold time after CLK↓		1.5		1.5		ns

<sup>&</sup>lt;sup>‡</sup> This parameter is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V<sub>CC</sub>.

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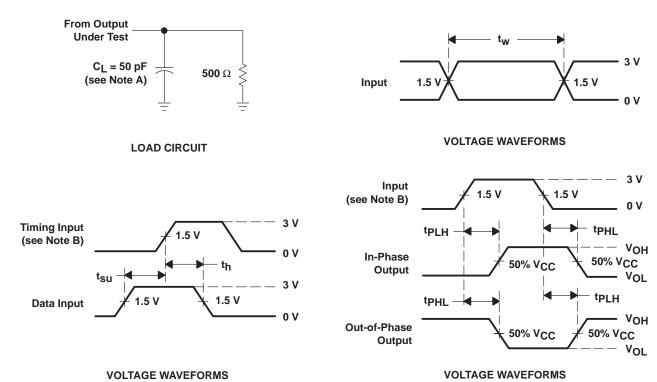
## switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T <sub>A</sub> = 25°C			MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIN	WAX	UNIT
f <sub>max</sub>			125			125		MHz
<sup>t</sup> PLH	PDE 01 P	Q or Q	1.5	3.6	6.3	1.5	6.8	ns
<sup>t</sup> PHL	PRE or CLR		1.5	4.6	7.4	1.5	8	115
<sup>t</sup> PLH	CLK	0	1.5	4.2	7	1.5	7.7	ne
tPHL	OLK	Q or Q	1.5	4.7	7.4	1.5	8.4	ns

### operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

	PARAMETER	ER TEST CONDITIONS			
C <sub>pd</sub>	Power dissipation capacitance per flip-flop	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	39	pF	

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_f = 3 \text{ ns}$ ,  $t_f = 3 \text{ ns}$ .
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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